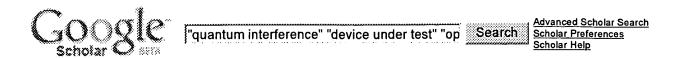
Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	1	(interfer\$ and quantum and ((device near under near test) or DUT) and (characteristic or property)).clm.	US-PGPUB	OR	OFF	2005/12/06 18:10

Ref	Hits	Search Query	DBs	Default	Plurals	Time Stamp
#		,		Operator		
L1	4	"643907".ap.	US-PGPUB; USPAT	OR	OFF	2005/12/06 13:50
L2	54849	quantum	US-PGPUB; USPAT	OR	OFF	2005/12/06 13:50
L3	375600	interference or interferometer	US-PGPUB; USPAT	OR	OFF	2005/12/06 13:50
L4	1724	2 near 3	US-PGPUB; USPAT	OR	OFF	2005/12/06 13:50
L5	8596	DUT or (device near under near test)	US-PGPUB; USPAT	OR	OFF	2005/12/06 13:51
L6	5	4 same 5	US-PGPUB; USPAT	OR	OFF	2005/12/06 13:52
L7	670379	interfer or interfere or interfering or interference or interferometer or interferometry or interferometric	US-PGPUB; USPAT	OR	OFF	2005/12/06 13:52
L8	1749	2 near 7	US-PGPUB; USPAT	OR	OFF	2005/12/06 13:52
L9	5	5 same 8	US-PGPUB; USPAT	OR	OFF	2005/12/06 13:52
L10	19	5 and 8	US-PGPUB; USPAT	OR	OFF	2005/12/06 13:52
L11	28379	optical near (characteristic or quality or quantity or property or trademark or trait)	US-PGPUB; USPAT	OR	OFF	2005/12/06 15:34
L12	2544640	measur\$5 or detect\$5 or test\$5	US-PGPUB; USPAT	OR	OFF	2005/12/06 13:54
L13	4431	11 with 12	US-PGPUB; USPAT	OR	OFF	2005/12/06 13:54
L14	45	11 with 12 with 5	US-PGPUB; USPAT	OR	OFF	2005/12/06 13:56
L15	3	14 and 8	US-PGPUB; USPAT	OR	OFF	2005/12/06 14:17
L16	1208	356/73.1.ccls.	US-PGPUB; USPAT	OR	OFF	2005/12/06 14:17
L17	3	16 and 8	US-PGPUB; USPAT	OR	OFF	2005/12/06 14:42
L18	395	356/450.ccls.	US-PGPUB; USPAT	OR	OFF	2005/12/06 14:42
L19	4	18 and 8	US-PGPUB; USPAT	OR	OFF	2005/12/06 15:08
L20	465	356/477.ccls.	US-PGPUB; USPAT	OR	OFF	2005/12/06 15:08

L21	4	20 and 8	US-PGPUB; USPAT	OR	OFF	2005/12/06 15:32
L22	9472	quantum	EPO; JPO; IBM_TDB	OR	OFF	2005/12/06 15:32
L23	77254	interfer or interfere or interfering or interference or interferometer or interferometry or interferometric	EPO; JPO; IBM_TDB	OR	OFF	2005/12/06 15:33
L24	1700	DUT or (device near under near test)	EPO; JPO; IBM_TDB	OR	OFF	2005/12/06 15:34
L25	5878	optical near (characteristic or quality or quantity or property or trademark or trait)	EPO; JPO; IBM_TDB	OR	OFF	2005/12/06 15:34
L26	1574393	measur\$5 or detect\$5 or test\$5	EPO; JPO; IBM_TDB	OR	OFF	2005/12/06 15:34
L27	639	22 near 23	EPO; JPO; IBM_TDB	OR	OFF	2005/12/06 15:34
L28	1	27 and 24	EPO; JPO; IBM_TDB	OR	OFF	2005/12/06 15:34



Tip: Try removing quotes from your search to get more results.

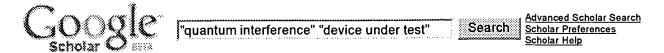
Your search - "quantum interference" "device under test" "optical characteristic" - did not match any articles.

Suggestions:

- Make sure all words are spelled correctly.
- Try different keywords.
- Try more general keywords.
- Try fewer keywords.
- Try your query on the entire web.

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Results 1 - 10 of about 23 for "quantum interference" "device under test". (0.01 seconds)

Resistance fluctuations in GaAs/Al x Ga As quantum point contact and Hall bar structures C Kurdak, CJ Chen, DC Tsui, S Parihar, S Lyon, GW ... - Phys Rev B, 1997 - link.aps.org ... So far quantum interference 1/f noise has only beenobserved in Bi wires14 and ... measurement where a dc voltage bias is applied to the device under test and the ... Cited by 7 - Web Search - adsabs.harvard.edu

First Space Test of High-T SQUIDs

M Klinger, JH Hinken, SS Tinchev, HTSS Experiment - IEEE TRANSACTIONS ON APPLIED SUPERCONDUCTIVITY, 1995 - ieeexplore.ieee.org ... I.INTRODUCTION Superconducting quantum interference devices (SQUID) are one of the first ... The device under test was a chip with 16 RF SQUIDs fabricated on a 10 ... Cited by 1 - Web Search - ieeexplore.ieee.org

... chip package with TDR (time domain reflectometry) and SQUID (superconducting quantum interference ...

L Cao, HB Chong, JM Chin, RN Master - Electronics Packaging Technology Conference, 2002. 4th, 2002 - ieeexplore.ieee.org

... Time Domain Reflectometty (TDR) and scanning Superconducting **Quantum Interference** Device (SQUID ... b obtain the information about the **device under test** (DUT). ... Web Search - <u>ieeexplore.ieee.org</u>

NEAR-FIELD MEASUREMENT OF MICROWAVE ACTIVE DEVICES

D Gasquet, L Nativel, C Arcambal, M Castagne, F ... - amsacta.cib.unibo.it ... propose different techniques using super conducting quantum interference devices (SQUID) [1 ... synthesizer allows us to feed (if necessary) the device under test. ... View as HTML - Web Search

Realization of a Charge Transformer; A Noise Matching Device for Single Electron Transistor

K Lewis, C Kurdak, S Krishna, P Bhattacharya - American Physical Society, Annual APS March Meeting, March ..., 2002 - adsabs.harvard.edu

... under test. The function of a charge transformer is analogous to that of a flux transformer commonly used with superconducting quantum interference devices ... Web Search

<u>Charge Transformer to Enhance Noise Performance of Single Electron Transistor Amplifiers in High ...</u>

KM Lewis, C Kurdak - American Physical Society, Annual March Meeting, March 12-16 ..., 2001 - adsabs.harvard.edu

... of a flux transformer commonly used with superconducting **quantum interference** devices (SQUIDs ... the SET and the capacitance of the **device under test**, respectively ... Web Search - adsabs.harvard.edu - link.aip.org

<u>Low-frequency flux noise and visualization of vortices in a YBa 2 Cu 3 O 7 dc SQUID washer</u> with an ...

R Straub, S Keil, R Kleiner, D Koelle - Arxiv preprint cond-mat/0104386, 2001 - arxiv.org ... flux (vortices) in direct current (dc) superconducting quantum interference devices (SQUIDs ... to the SQUID loop, where the SQUID itself is the device under test. ... View as HTML - Web Search - adsabs.harvard.edu

ASQUID Picovoltmeter Working at 77 K

T Eriksson, J Blomgren, D Winkler, YQ Shen - sensor.northgrum.com ... I. I NTRODUCTION Voltmeters based on Superconducting QUantum Interference Devices (SQUID) was one ... The device under test was made from a 150 nm thick YBCO film ... View as HTML - Web Search - es.northropgrumman.com

A SQUID Picovoltmeter Working at 77 K

J Blomgren, D Winkler, T Holst, YQ Shen - IEEE TRANSACTIONS ON APPLIED SUPERCONDUCTIVITY, 1999 - ieeexplore.ieee.org

... The device under test was made from a 150 nm thick YBCO film ... picovoltmeter based on the direct current superconducting quantum interference device with ... Web Search

High-7 Superconducting Monolithic Phase Shifter

CL Pettiette-Hall, JF Burch - IEEE TRANSACTIONS ON APPLIED SUPERCONDUCTIVITY, 1992 ieeexplore.ieee.org

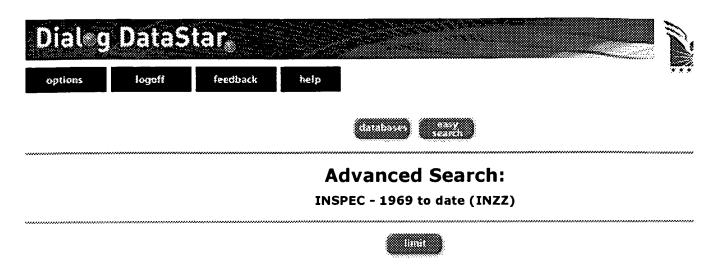
... line is actively coupled to an array of superconducting quantum interference devices (SQUID ... The device under test (DUT) had 3-dB pads on the input and output to ... Web Search

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"quantum interference" "device unde Search

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Search history:

No.	Database	Search term	Info added since	Results	
1	INZZ	quantum ADJ interference	unrestricted	11602	<u>show titles</u>
2	INZZ	quantum ADJ interfer\$	unrestricted	11894	show titles
3	INZZ	device ADJ under ADJ test OR DUT	unrestricted	1422	show titles
4	INZZ	optical ADJ (characteristic OR property)	unrestricted	1507	show titles
5	INZZ	2 AND 3 AND 4	unrestricted	0	-
6	INZZ	device ADJ under ADJ test	unrestricted	1110	show titles
7	INZZ	2 AND 6	unrestricted	0	-
8	INZZ	1 AND 6	unrestricted	0	-

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Enter your search term(s): Search tips \square Thesaurus mapping					
	whole document	:			
Information added since: or: none (YYYYMMDD)		(LUITE)			
Select special search terms from the following list(s) Publication year Classification codes A: Physics, 0-1	s):				
Classification codes A: Physics, 2-3					
Classification codes A: Physics, 4-5					
Classification codes A: Physics, 6					
Classification codes A: Physics, 7					
Classification codes A: Physics, 8					
Classification codes A: Physics, 9					